



Remote Sensing in Meteorology

Guest Editors:

Dr. Yahui Che

School of Engineering and Built Environment, Griffith University, Kessels Road, Nathan, QLD 4111, Australia

Dr. Lu She

School of Geography and Planning, Ningxia University, Yinchuan 750021, China

Deadline for manuscript submissions:

closed (20 February 2024)

Message from the Guest Editors

Dear Colleagues,

Satellite images provide a wide view of meteorological conditions in a sub-day frequency. With the development of meteorological satellites, a large amount of satellite measurements have been inversed into physical information on clouds, temperature, precipitation, wind field, snow and ice cover, and so on. Retrieval algorithms based on physical mechanism, empirical relationships, and machine learning have all contributed to the developments and applications of meteorological products. Meanwhile, validation work with high-quality ground-based filed observations is necessary for meteorological research and improvement to these algorithms and products.

This Special Issue focuses on the development of retrieval algorithms for meteorological information, validation of meteorological products, and application of satellite measurements on meteorology.

For more information on the Special Issue, please visit LINK

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Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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